

Search Notes**Application/Control No.**

10/584,839

Examiner

/Yonel Beaulieu/

**Applicant(s)/Patent under
Reexamination**

CHO ET AL.

Art Unit

3661

SEARCHED

Class	Subclass	Date	Examiner
701	200	9/10/2009	YB
	117		
	211		
342	357.09		
	357.1		
370	328		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST	9/10/2009	YB